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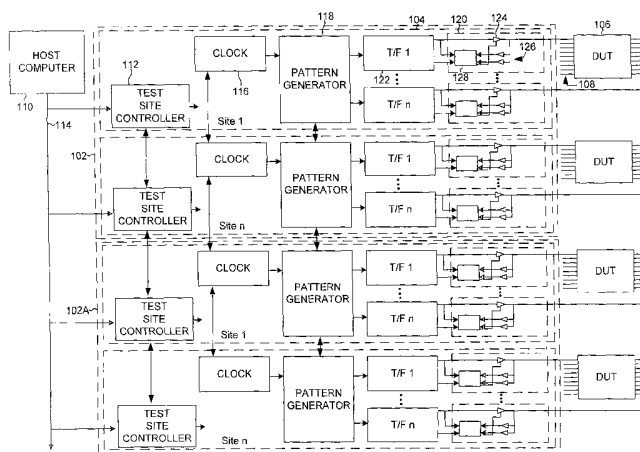
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(54) Title: STACKABLE SEMICONDUCTOR TEST SYSTEM AND METHOD FOR OPERATING SAME



(57) Abstract: A tester configured to stack with at least one other tester (102f) to provide a test system for simultaneously testing a number of devices in parallel on different testers (102), or testing a device having more pins than can be accommodated by a single tester (102). The tester (102) includes a test site (104) with a number of pin electronics channel (120), an interface (148) for interfacing with the device, and a computer for interfacing with a host computer (110) in the test system. The testers (102) can be fastened directly to one another or to a common frame. Preferably, the interface (148) enables a single device board (160) to simultaneously engage interfaces (148) on multiple testers (102). More preferably, the interface (148) extends from a top surface of the tester (102) to engage the device board (160). Vents (144,146) and front surfaces of an enclosure enables movement of air to cool components of the tester (102) without interference from testers (102) on either side or back of the enclosure.



WO 03/029833 A3



For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

INTERNATIONAL SEARCH REPORT

International application No.

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A. CLASSIFICATION OF SUBJECT MATTER

IPC(7) : G01R 31/00
 US CL : 324/158.1,73.1,760

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
 U.S. : 324/158.1,73.1,760,765; 714/724,733; 165/80.3;

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched
 NONE

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)
 NONE

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 4,729,246 A (MELGAARD ET AL.) 08 MARCH 1988, See entire document.	1-43
A	US 5,650,732 A (SAKAI) 22 JULY 1997, see entire document.	1-43

Further documents are listed in the continuation of Box C. See patent family annex.

* Special categories of cited documents:	"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
"A" document defining the general state of the art which is not considered to be of particular relevance	"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
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